

### **Description**

The VSM25P06 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge .This device is well suited for high current load applications.

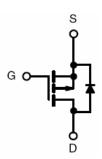
#### **General Features**

- $V_{DS}$  =-60V, $I_{D}$  =-25A  $R_{DS(ON)}$  <45m $\Omega$  @  $V_{GS}$ =-10V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

### **Application**

- High side switch for full bridge converter
- DC/DC converter for LCD display





Schematic Diagram

### **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM25P06-TC	VSM25P06	TO-220C	-	-	-

### Absolute Maximum Ratings (T<sub>C</sub>=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	VDS	-60	V	
Gate-Source Voltage	V <sub>G</sub> s	±20	V	
Drain Current-Continuous	I <sub>D</sub>	-25	А	
Drain Current-Continuous(T <sub>C</sub> =100°ℂ)	I <sub>D</sub> (100℃)	-17.7	Α	
Pulsed Drain Current	I <sub>DM</sub>	-60	А	
Maximum Power Dissipation	P <sub>D</sub>	90	W	
Derating factor		0.72	W/℃	





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Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	300	mJ	
Operating Junction and Storage Temperature Range	$T_J, T_STG$	-55 To 150	$^{\circ}\!\mathbb{C}$	

### **Thermal Characteristic**

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	R <sub>0JC</sub>	1.4	°C/W
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## Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics	·		•				
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =-250μA	-60	-	-	V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =-60V,V <sub>GS</sub> =0V	-	-	-1	μΑ	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA	
On Characteristics (Note 3)	·		•				
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=-250\mu A$	-2	-2.9	-3.5	V	
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A	-	39	45	mΩ	
Forward Transconductance	<b>g</b> Fs	V <sub>DS</sub> =-10V,I <sub>D</sub> =-10A	-	25	-	S	
Dynamic Characteristics (Note4)	•		•			•	
Input Capacitance	C <sub>lss</sub>	1/ 00/// 01/	-	3430	-	PF	
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ =-30V, $V_{GS}$ =0V,	-	391	-	PF	
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.0MHz	-	272	-	PF	
Switching Characteristics (Note 4)	•		•			•	
Turn-on Delay Time	t <sub>d(on)</sub>		-	12	-	nS	
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =-30V, $R_L$ =1.5 $\Omega$ ,	-	15	-	nS	
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =-10 $V$ , $R_{G}$ =3 $\Omega$	-	38	-	nS	
Turn-Off Fall Time	t <sub>f</sub>		-	15	-	nS	
Total Gate Charge	Qg	V 201 20A	-	46		nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ =-30, $I_{D}$ =-20A, $V_{GS}$ =-10V	-	9.5		nC	
Gate-Drain Charge	$Q_{gd}$	V <sub>GS</sub> =-10V	-	10.5		nC	
Drain-Source Diode Characteristics	•		•			•	
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =-10A	-		-1.2	V	
Diode Forward Current (Note 2)	Is		-	-	-25	Α	
Reverse Recovery Time	t <sub>rr</sub>	TJ = 25°C, IF =- 10A	-	47		nS	
Reverse Recovery Charge	Qrr	di/dt = -100A/µs(Note3)	-	53		nC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD					

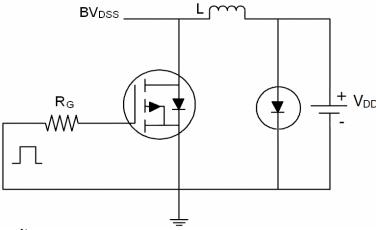
#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width ≤  $300\mu$ s, Duty Cycle ≤ 2%.
- **4.** Guaranteed by design, not subject to production
- **5.**  $E_{AS}$  condition:  $Tj=25^{\circ}C$ , $V_{DD}=-20V$ , $V_{G}=-10V$ ,L=1mH, $Rg=25\Omega$ , $I_{AS}=33A$

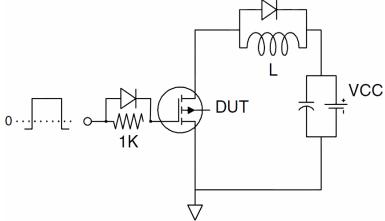


## **Test Circuit**

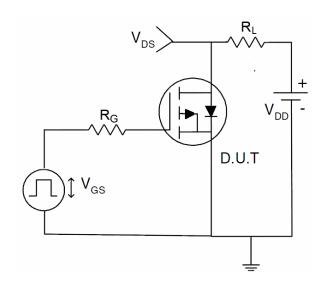
# 1) E<sub>AS</sub> Test Circuit



# 2) Gate Charge Test Circuit

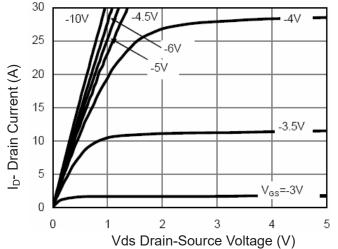


## 3) Switch Time Test Circuit

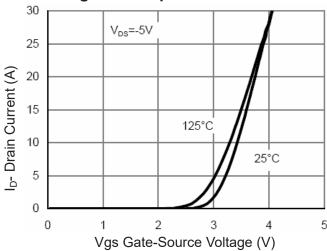








**Figure 1 Output Characteristics** 



**Figure 2 Transfer Characteristics** 

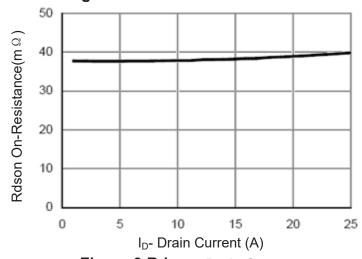
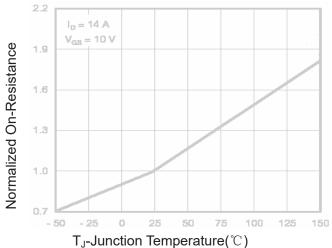
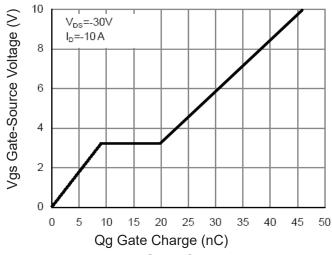


Figure 3 Rdson- Drain Current



**Figure 4 Rdson-Junction Temperature** 



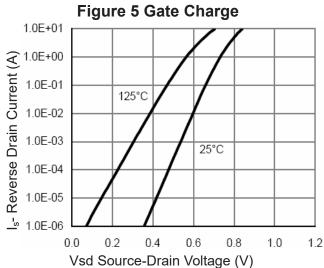
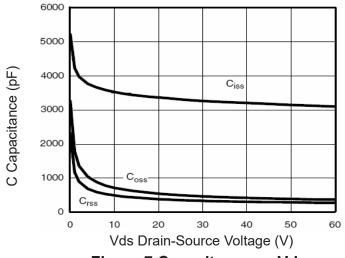


Figure 6 Source- Drain Diode Forward





BV<sub>DSS</sub> (norm)  $V_{\text{CS}} = 0$   $I_{\text{D}} = 250 \mu\text{A}$  1.2 1.1 1.0 0.9 0.8 -50 0 50 100  $T_{\text{J}}(^{\circ}\text{C})$  T<sub>J</sub>-Junction Temperature( $^{\circ}\text{C}$ )

Figure 9 BV<sub>DSS</sub> vs Junction Temperature

25

(V) tuesum 10

10

0 25 50 75 100 125 150

TJ-Junction Temperature(°C)





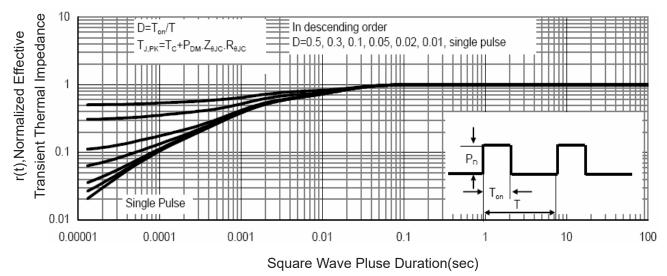


Figure 11 Normalized Maximum Transient Thermal Impedance